INSTITUTE OF AERONAUTICAL ENGINEERING

(Autonomous)

Dundigal, Hyderabad -500 043

ELECTRONICS AND COMMUNICATION ENGINEERING

COURSE DESCRIPTOR

Course Title	ELECTRONIC DEVICES AND CIRCIUTS LAB						
Course Code	AECB	AECB09					
Programme	B.Tech						
Semester	III	ECE	2				
Course Type	Core						
Regulation	IARE -	R18					
	Lectures Tutorials Practical Credits						
	3 1.5						
Course Coordinator	Mrs. G .Mary Swarna Latha, Assistant professor						
Course Faculty			ndar basha, Assi vani, Assistant pr	1			

I. COURSE OVERVIEW:

This lab complements the electronic devices circuits course. Students will gain practical experience with designing and implementing concepts of electronic devices and circuits such as diodes, transistor configurations, rectifiers, biasing circuits and amplifiers.

II. COURSE PRE-REQUISITES:

Level	Course Code	Semester	Prerequisites	Credits
UG	AHSB04	Ι	Waves and Optics	4

III. MARKS DISTRIBUTION:

Subject	SEE Examination	CIA Examination	Total Marks
Electronic devices and circuits lab	70 Marks	30 Marks	100

IV. DELIVERY / INSTRUCTIONAL METHODOLOGIES:

×	CHALK & TALK	~	VIVA	×	ASSIGNMENTS	×	MOOCS
~	LCD / PPT	×	SEMINARS	~	MINI PROJECT	×	VIDEOS
×	✗ OPEN ENDED EXPERIMENTS						

V. EVALUATION METHODOLOGY:

Each laboratory will be evaluated for a total of 100 marks consisting of 30 marks for internal assessment and 70 marks for semester end lab examination. Out of 30 marks of internal assessment, continuous lab assessment will be done for 20 marks for the day to day performance and 10 marks for the final internal lab assessment.

Semester End Examination (SEE): The semester end lab examination for 70 marks shall be conducted by two examiners, one of them being Internal Examiner and the other being External Examiner, both nominated by the Principal from the panel of experts recommended by Chairman, BOS.

20 %	To test the preparedness for the experiment.				
20 %	To test the performance in the laboratory.				
20 %	To test the calculations and graphs related to the concern experiment.				
20 %	To test the results and the error analysis of the experiment.				
20 %	To test the subject knowledge through viva – voce.				

The emphasis on the experiments is broadly based on the following criteria:

Continuous Internal Assessment (CIA):

CIA is conducted for a total of 30 marks (Table 1), with 20 marks for continuous lab assessment during day to day performance, 10 marks for final internal lab assessment.

	Table 1: Assessment pattern for CIA					
Component		Laboratory	Total Marks			
Type of Assessment	Day to day performance	Final internal lab assessment				
CIA Marks	20	10	30			

Continuous Internal Examination (CIE):

One CIE exams shall be conducted at the end of the 16th week of the semester. The CIE exam is conducted for 10 marks of 3 hours duration.

Preparation	Performance	Calculations and Graph	Results and Error Analysis	Viva	Total
2	2	2	2	2	10

VI. HOW PROGRAM OUTCOMES ARE ASSESSED:

	Program Outcomes (POs)	Strength	Proficiency assessed by
PO 1	Engineering knowledge: Apply the knowledge of mathematics,	3	Lab related
	science, engineering fundamentals, and an engineering		Exercises
	specialization to the solution of complex engineering problems.		
PO 2	Problem analysis: Identify, formulate, review research	3	Lab related
	literature, and analyze complex engineering problems reaching		Exercises/Mini
	substantiated conclusions using first principles of mathematics,		projects
	natural sciences, and engineering sciences		

	Program Outcomes (POs)	Strength	Proficiency assessed by
PO 5	Modern tool usage: Create, select, and apply appropriate techniques, resources, and modern engineering and IT tools including prediction and modeling to complex engineering activities with an understanding of the limitations.	3	Lab related Exercises
PO 11	Life-long learning: Recognize the need for, and have the preparation and ability to engage in independent and life-long learning in the broadest context of technological change.	2	Lab related Exercises
PO 12	Project management and finance: Demonstrate knowledge and understanding of the engineering and management principles and apply these to one's own work, as a member and leader in a team, to manage projects and in multidisciplinary environments.	2	Lab related Exercises

3= **High; 2** = **Medium; 1** = **Low**

VII. HOW PROGRAM SPECIFIC OUTCOMES ARE ASSESSED:

	Program Specific Outcomes	Level	Proficiency assessed by
PSO1	Professional Skills: An ability to understand the basic concepts in Electronics & Communication Engineering and to apply them to various areas, like Electronics, Communications, Signal processing, VLSI, Embedded systems etc., in the design and implementation of complex systems.	3	Lab related exercises.
PSO2	Problem-Solving Skills: An ability to solve complex Electronics and communication Engineering problems, using latest hardware and software tools, along with analytical skills to arrive cost effective and appropriate solutions.	1	Lab related exercises.
PSO3			-

3= **High**; **2** = **Medium**; **1** = **Low**

VII. COURSE OBJECTIVES:

The	The course should enable the students to:				
Ι	Implement and study the characteristics of Diodes and Transistors.				
II	Illustrate the concept of rectification using half wave and full wave rectifiers				
III	Design and Construct different amplifier circuits.				

IX. COURSE OUTCOMES (COs):

COs	Course Outcome	CLOs	Course Learning Outcome
CO 1	Identify and understand different electronic components used in the laboratory.	CLO 1	Understand identification, specifications, testing of R, L, C components (Color Codes), potentiometers, switches (SPDT, DPDT and DIP), coils, gang condensers, relays, bread boards, PCBs, identification, specifications and testing of active devices, diodes, BJTs, low power JFETs, MOSFETs, power transistors,

			LEDs, LCDs, optoelectronic devices, SCR, UJT, DIACs.
		CLO 2	Study and operation of a. Multimeters (Analog and Digital) b. Function Generator c. Regulated Power Supplies d. Study and Operation of CRO
CO 2	Verify V-I characteristics of PN and Zener diode and its use in rectifier circuits.	CLO 3	Verification of V-I characteristics of PN diode and calculate static and dynamic resistance using hardware and digital simulation.
		CLO 4	Verification of V-I characteristics of Zener diode and perform Zener diode as a Voltage regulator using hardware and digital simulation.
		CLO 5	Verification of half wave rectifier without and with filters using hardware and digital simulation.
		CLO 6	Verification of Full Wave Rectifier without and with filters using hardware and digital simulation.
CO 3	Verify input and output characteristics of CB,CE configuration and their use in	CLO 7	Verification of Input and Output characteristics of CB configuration using hardware and digital simulation.
	amplifiers.	CLO 8	Verification of Input and Output Characteristics of CE configuration using hardware and digital simulation.
		CLO 9	Determine the Gain and Bandwidth of CE amplifier using hardware and digital simulation.
		CLO 10	Determine the Gain and Bandwidth of CC amplifier using hardware and digital simulation.
CO 4	Verify V-I Characteristics of UJT and SCR.	CLO 11	Verification of V-I Characteristics of UJT using hardware and digital simulation.
		CLO 12	Verification of V-I Characteristics of SCR using hardware and digital simulation.
CO 5	Verify V-I Characteristics of FET and its use in amplifiers.	CLO 13	Verification of V-I Characteristics of FET using digital simulation.
		CLO 14	Determine the Gain and Bandwidth of CS amplifier using digital simulation
		CLO 15	Determine the Gain and Bandwidth of CS amplifier using digital simulation.

X. MAPPING COURSE OUTCOMES LEADING TO THE ACHIEVEMENT OF PROGRAM OUTCOMES AND PROGRAM SPECIFIC OUTCOMES:

Course Outcomes	Program Outcomes (POs)									
(COs)	PO1	PO2	PO5	PO11	PO12	PSO1	PSO2	PSO3		
CO 1	3		3							
CO 2	3	3	3	2	2	3	1			
CO 3	3	3	3	2	2	3	1			

Course Outcomes	Program Outcomes (POs)								
(COs)	PO1	PO2	PO5	PO11	PO12	PSO1	PSO2	PSO3	
CO 4	3		3						
CO 5	3	3	3	2	2	3	1		

3= High; 2 = Medium; 1 = Low

XI. COURSE LEARNING OUTCOMES (CLOs):

CLO Code	CLO's	At the end of the course, the student will have the ability to:	PO's Mapped	Strength of
				Mapping
AECB09.01	CLO 1	Understand identification, specifications,	PO 1	3
		testing of R, L, C components (Color Codes),	PO 5	
		potentiometers, switches (SPDT, DPDT and		
		DIP), coils, gang condensers, relays, bread		
		boards, PCBs, identification, specifications and		
		testing of active devices, diodes, BJTs, low		
		power JFETs, MOSFETs, power transistors,		
		LEDs, LCDs, optoelectronic devices, SCR,		
	CT O O	UJT,DIACs.	DO 1	
AECB09.02	CLO 2	Study and operation of a. Multimeters (Analog	PO 1	3
		and Digital) b. Function Generator c.		
		Regulated Power Supplies d. Study and		
AECD00.02	CLO 3	Operation of CRO Verification of V-I characteristics of PN diode	PO 1	3
AECB09.03	CLU 3		PO 1 PO 2	3
		and calculate static and dynamic resistance using hardware and digital simulation.	PO 2	
AECB09.04	CLO 4	Verification of V-I characteristics of Zener	PO 1	3
AECD09.04	CLU4	diode and perform Zener diode as a Voltage	PO 1 PO 5	5
		regulator using hardware and digital	105	
		simulation.		
AECB09.05	CLO 5	Verification of half wave rectifier without and	PO 1	3
		with filters using hardware and digital	PO 11	
		simulation.		
AECB09.06	CLO 6	Verification of Full Wave Rectifier without	PO 1	3
		and with filters using hardware and digital	PO 12	
		simulation.		
AECB09.07	CLO 7	Verification of Input and Output	PO 1	3
		characteristics of CB configuration using		
		hardware and digital simulation.		
AECB09.08	CLO 8	Verification of Input and Output	PO 1	3
		Characteristics of CE configuration using	PO 2	
		hardware and digital simulation.		
AECB09.09	CLO 9	Determine the Gain and Bandwidth of CE	PO 1	3
		amplifier using hardware and digital	PO 5	
		simulation.		
AECB09.10	CLO 10	Determine the Gain and Bandwidth of CC	PO 1	3
		amplifier using hardware and digital	PO 11	
		simulation.		

AECB09.11	CLO 11	Verification of V-I Characteristics of UJT	PO 1	3
		using hardware and digital simulation.	PO 5	
AECB09.12	CLO 12	Verification of V-I Characteristics of SCR	PO 1	3
		using hardware and digital simulation.	PO 5	
AECD00.12	CLO 13	Verification of V-I Characteristics of FET	PO 1	3
AECB09.13	CLO 13	using digital simulation.	PO 2	
AECB09.14	CLO 14	Determine the Gain and Bandwidth of CS	PO 5	3
		amplifier using digital simulation	PO 11	
AECB09.15	CLO 15	Determine the Gain and Bandwidth of CS	PO 1	3
		amplifier using digital simulation.	PO 12	

3= High; 2 = Medium; 1 = Low

XII. MAPPING COURSE LEARNING OUTCOMES LEADING TO THE ACHIEVEMENT OF PROGRAM OUTCOMES AND PROGRAM SPECIFIC OUTCOMES:

Course Learning	g Program Outcomes (POs)								gram Sp comes (l						
Outcomes	PO1	PO2	PO3	PO4	PO5	PO6	PO7	PO8	PO9	PO10	PO11	PO12	PSO1	PSO2	PSO3
CLO 1	3				3										
CLO 2	3														
CLO 3	3	3											3	1	
CLO 4	3				3								3	1	
CLO 5	3										2		3	1	
CLO 6	3											2	3	1	
CLO 7	3												3	1	
CLO 8	3	3											3	1	
CLO 9	3				3								3	1	
CLO 10	3										2		3	1	
CLO 11	3				3										
CLO 12	3				3										
CLO 13	3	3											3	1	
CLO 14					3						2		3	1	
CLO 15	3											2	3	1	

3 = High; **2** = Medium; **1** = Low

XIII. ASSESSMENT METHODOLOGIES-DIRECT

CIE Exams	PO 1, PO2,PO 5	SEE Exams	PO 1, PO 2, PO5, PSO 1	Assignments	-	Seminars	-
Laboratory Practices	PO 11,PO 12	Student Viva	PSO1,PSO2	Mini Project	-	Certification	-
Term Paper	-						

XIV. ASSESSMENT METHODOLOGIES-INDIRECT:

~	Early Semester Feedback	~	End Semester OBE Feedback
×	Assessment of Mini Projects by Experts		

XV. SYLLABUS:

WEEK-1	ELECTRONIC WORKSHOP PRACTICE								
Identification, specifications, testing of R, L, C components (Color Codes), potentiometers, switches (SPDT, DPDT and DIP), coils, gang condensers, relays, bread boards, PCBs, identification, specifications and testing of active devices, diodes, BJTs, low power JFETs, MOSFETs, power transistors, LEDs, LCDs, optoelectronic devices, SCR, UJT, DIACs.									
WEEK-2	ELECTRONIC WORKSHOP PRACTICE								
• •	Study and operation of a. Multimeters (Analog and Digital) b. Function Generator c. Regulated Power Supplies d. Study and Operation of CRO.								
WEEK-3	EK-3 PN DIODE CHARACTERISTICS								
	Verification of V-I characteristics of PN diode and calculate static and dynamic resistance using hardware and digital simulation.								
WEEK-4	K-4 ZENER DIODE CHARACTERISTICS AND VOLTAGE REGULATOR								
	Verification of V-I characteristics of Zener diode and perform Zener diode as a Voltage regulator using hardware and digital simulation.								
WEEK-5	HALF WAVE RECTIFIER								
Verification of ha	If wave rectifier without and with filters using hardware and digital simulation.								
WEEK-6	FULL WAVE RECTIFIER								
Verification of Fu	Il Wave Rectifier without and with filters using hardware and digital simulation.								
WEEK-7	TRANSISTOR CB CHARACTERISTICS								
Verification of Inp	out and Output characteristics of CB configuration using hardware and digital simulation.								
WEEK-8	TRANSISTOR CE CHARACTERISTICS								
Verification of Inp	Verification of Input and Output Characteristics of CE configuration using hardware and digital simulation.								
WEEK-9	WEEK-9 FREQUENCY RESPONSE OF CE AMPLIFIER								
Determine the Gai	n and Bandwidth of CE amplifier using hardware and digital simulation.								
WEEK-10	WEEK-10 FREQUENCY RESPONSE OF CC AMPLIFIER								
Determine the Gain and Bandwidth of CC amplifier using hardware and digital simulation.									

WEEK-11	UJT CHARACTERISTICS							
Verification of V-	Verification of V-I Characteristics of UJT using hardware and digital simulation.							
WEEK-12	WEEK-12 SCR CHARACTERISTICS							
Verification of V-	I Characteristics of SCR using hardware and digital simulation.							
WEEK-13	WEEK-13 FET CHARACTERISTICS							
Verification of V-I Characteristics of FET using digital simulation								
WEEK-14	FREQUENCY RESPONSE OF CS AMPLIFIER							
Determine the Gai	Determine the Gain and Bandwidth of CS amplifier using digital simulation.							
WEEK-15	FREQUENCY RESPONSE OF CD AMPLIFIER							
Determine the Gai	n and Bandwidth of CS amplifier using digital simulation							
Reference Books:								
1. J. Millman, C	C.C.Halkias, Millman's, "Integrated Electronics", Tata McGraw Hill, 2 nd Edition, 2001.							
2. J. Millman,								
McGraw Hill, 2 nd Edition, 1998.								
3. Mohammad Rashid, "Electronic Devices and Circuits", Cengage learning, 1 st Edition, 2014.								
4. David A. Bell, "Electronic Devices and Circuits", Oxford University Press, 5 th Edition, 2009.								
Web References:								
1 https://arabiv	https://archive.org/datails/ElectronicDavicesCircuits							

- 1. https://archive.org/details/ElectronicDevicesCircuits
- 2. http://www.tedpavlic.com/teaching/osu/ece327/

XVI. COURSE PLAN:

The course plan is meant as a guideline. Probably there may be changes.

Lecture	CLO	Tanias to be servered
No.	CLO	Topics to be covered
1-3	Understand the electronic components	Electronic Workshop Practice
	and identification	
4-6	Understand the pn junction diode	PN Junction diode characteristics
	characteristics.	A. Forward bias B. Reverse bias.
7-9	Understand the zener diode	Zener diode characteristics and voltage regulator
	characteristics.	
10-12	Analyze the half wave rectifier output	Half wave Rectifier with and without filter.
	waveform and parameters.	
13-15	Analyze the full wave rectifier output	Full wave Rectifier with and without filter.
	waveform and parameters.	
16-18	Design transistor under CB configuration	Transistor CB characteristics (Input and Output)
	and analyze its characteristics.	
19-21	Design transistor under CE configuration	Transistor CE characteristics (Input and Output)
	and analyze its characteristics.	
22-24	Analyze the amplifier gain using CE and	Frequency response of CE Amplifier
	analyze its characteristics.	
25-27	Analyze the amplifier gain using CC and	Frequency response of CC Amplifier
	analyze its characteristics.	
28-30	Understand UJT characteristics and	UJT characteristics.
	analyze its characteristics.	
31-33	Understand SCR characteristics and	SCR characteristics
	analyze its characteristics.	

34-36	Understand FET characteristics and analyze its characteristics.	FET Characteristics
37-39	Analyze the frequency response of CS amplifier.	Frequency Response Of CS Amplifier
40-42	Analyze the frequency response of CD amplifier gain	Frequency Response Of CD Amplifier

XVII. GAPS IN THE SYLLABUS - TO MEET INDUSTRY / PROFESSION REQUIREMENTS:

S No	Description	Proposed Actions	Relevance With POs	Relevance With PSOs
1	Design of electronic circuits on PCB boards.	Laboratory Practices	PO 1, PO 2,PO 5	PSO 1

Prepared by: Mrs. G Mary Swarna Latha

HOD, ECE